

Application of resonant ultrasound spectroscopy to β -Ga₂O₃

β -Ga₂O₃ に対する共振超音波スペクトロスコピーの適用

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1. Introduction

Beta-type gallium oxide (β -Ga₂O₃) attracts much attention because of its great potential to high-power electron devices. Its bandgap is second largest among semiconductors, which realizes extremely high breakdown electric field. This characteristic makes β -Ga₂O₃ suitable material for power devices such as transistors and diodes; the Baliga figure of merit, which shows suitability for power devices, is about four times larger than that of GaN [1]. β -Ga₂O₃ has an advantage also in commercialization. A β -Ga₂O₃ bulk monocrystal can be produced by the same method as Si at low cost [2]. By contrast, fabrication of a GaN or a SiC single-crystal substrate by vapor-phase epitaxial methods requires great cost and energy. For these reasons, β -Ga₂O₃ is much superior in terms of device application than other wide-bandgap semiconductors for power devices. Recently, Ga₂O₃-based transistors are actively studied and developed, where it is important to clarify material properties of β -Ga₂O₃. The elastic constants of β -Ga₂O₃ are necessary to estimate performance of the transistors because strain in Ga₂O₃ layer, which is induced by mismatch of lattice constants between the different materials or is artificially introduced to increase the electron mobility, affects the device performance. It is, however, difficult to accurately measure all the elastic constants, C_{ij} of β -Ga₂O₃ due to its low crystallographic symmetry, and no study exists providing all the elastic constants.

Monoclinic β -Ga₂O₃ exhibits thirteen independent

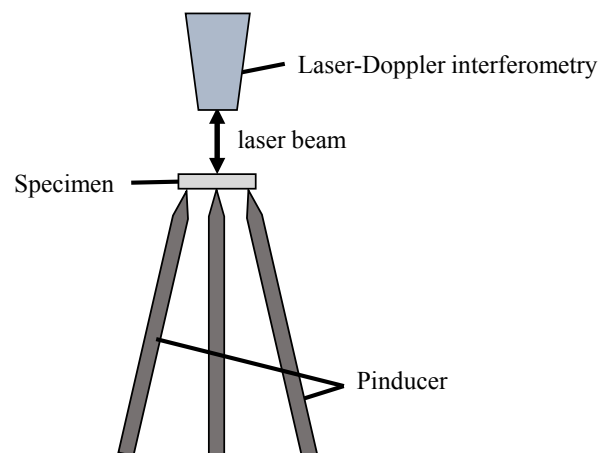
$$[C_{ij}] = \begin{bmatrix} C_{11} & C_{12} & C_{13} & 0 & C_{15} & 0 \\ C_{12} & C_{22} & C_{23} & 0 & C_{25} & 0 \\ C_{12} & C_{23} & C_{33} & 0 & C_{35} & 0 \\ 0 & 0 & 0 & C_{44} & 0 & C_{46} \\ C_{15} & C_{25} & C_{35} & 0 & C_{55} & 0 \\ 0 & 0 & 0 & C_{46} & 0 & C_{66} \end{bmatrix} \quad (1)$$

elastic constants:

Previously, all the 13 C_{ij} of a monoclinic single crystal have been determined using resonant ultrasound spectroscopy (RUS) [3]. The RUS method, however, requires unambiguous mode identification to obtain reliable results because it inversely deduces elastic constants by comparing the measured and calculated resonance frequencies. It is, therefore, necessary to know “good” initial guesses of the elastic constants for the correct mode identification; it is usually carried out by comparing measured resonance frequencies with those calculated from the initial guesses. Consequently, the standard RUS method is inapplicable to β -Ga₂O₃ because no reported values for elastic constants appear. Here, we apply the RUS/Laser technique [4], where it is possible to identify the resonant modes by measuring displacement distributions of a crystal surface through laser-Doppler interferometry and comparing them with computed distributions, to β -Ga₂O₃ in order to accurately determine elastic constants.

2. Experiment Procedure

We developed the tripod-type RUS with laser-Doppler interferometry as shown in Fig. 1 [5].



Free vibrations of the specimen can be excited and

Fig. 1 Schematic of the RUS/Laser measurement system.

detected by the needle piezoelectric transducers constituting a tripod. A laser beam was focused on the surface of the resonating specimen. A Doppler interferometry detects the frequency shift of the reflected beam and measures vertical component of velocity at the focal point. Vertical-velocity distributions are obtainable by scanning the whole surface of the specimen. The velocity distribution can be converted into the normal-displacement distribution due to harmonic oscillation, where there is a proportional relationship between maximum velocity and displacement. The mode identification is achieved by comparing measured and calculated displacement distribution because each resonant mode shows unique distribution.

We used high-quality β -Ga₂O₃ monocrystal, and three rectangular-parallelepiped specimens were prepared. The typical dimensions are 3.4 mm, 4.9 mm, and 3.6 mm. (The *b* and *c* axes are parallel to the 4.9-mm and 3.6-mm sides, respectively.) The measured mass density is 5.709 g/cm³. We deposited 100-nm Al on the specimen to reflect the laser beam.

3. Result and Discussion

We estimated the elastic constants of β -Ga₂O₃ through *ab-initio* calculation, which provided theoretical displacement distributions. Figure 2 compares calculated and measured displacement distributions on a resonating crystal surface. The agreement between them is enough to unambiguously identify the resonant modes.

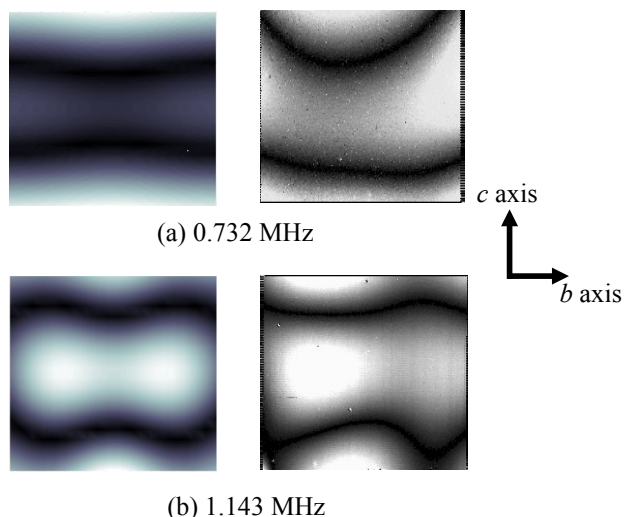


Fig. 2 Examples of calculated (left) and measured (right) displacement distributions for the β -Ga₂O₃ specimen. The bright and dark zones represent antinode and node, respectively. The values below the drawings indicate measured resonance frequencies.

Similar consistency appears for many other modes, which realizes the complete mode identification for β -Ga₂O₃. Hence, the RUS/Laser technique allows us to accurately determine elastic constants of β -Ga₂O₃ via the inverse calculation; the differences between the resultant and first-principle values of elastic constants are less than 3.2 %, including the off-diagonal components.

4. Conclusion

We measured elastic constants of β -Ga₂O₃, which doesn't have any reported values of them, by performing the unambiguous resonant-mode identification via the RUS/Laser technique. The measurements indicate that it is possible to observe the displacement distribution on a surface of the monoclinic material and precisely determine all the independent elastic constants using the technique.

References

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